

Notice of References Cited	Application/Control No. 09/882,361	Applicant(s)/Patent Under Reexamination PARK, MELVIN A.	
	Examiner Zia R. Hashmi	Art Unit 2881	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,403,952	06-2002	Whitehouse et al.	250/288
	B	US-6,403,953	06-2002	Whitehouse et al.	250/288
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Wang et al., "Apparatus and Method for Analyzing Samples in a Dual-Ion Trap Mass Spectrometer", Pub. No: 2002/0121594 A1, publication date: September 5, 2002.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.